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## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	31	fault AND (first NEAR second NEAR value) AND threshold AND "digital data"	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/06/13 06:04
S1	717	(324/509.ccls. OR 324/522.ccls. OR 324/140R.ccls.) AND @ad<"20020815"	US-PGP UB; USPAT; USOCR	AND	ON	2006/06/12 08:18
S2	469	(714/712.ccls.) AND @ad<"20020815"	US-PGP UB; USPAT; USOCR	AND	ON	2006/06/12 07:19
S3	44	714/816.ccls.	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/06/12 07:19

## EAST Search History

S4	49	715/715.ccls.	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/06/12 07:59
S5	14	compar??? NEAR3 mid?point	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/06/12 08:20
S6	1	(compar??? NEAR3 mid?level) AND fault	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/06/12 08:20

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S7	395	fault AND (first NEAR second NEAR value) AND threshold	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/06/13 07:28
S9	628	375/224.ccls. AND @ad<"20020815"	US-PGP UB; USPAT; USOCR	AND	ON	2006/06/12 09:32

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**Search for concept:**

A method for producing a fault signal indicating a fault in a transmission of a data signal transmitted using differential signaling on a data line having two signal lines, which comprises the steps of: comparing a first mid-level value having a potential in an area of a mid-point between a signal level on a first signal line and a signal level on a second signal line when transmitting a logic "1" with a second mid-level value formed when transmitting a logic "0"; and generating the fault signal if a discrepancy between the first and second mid-level values exceeds a predetermined

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L7	1	("first mid-level value" SAME "fault signal").clm.	US-PGP UB	AND	ON	2006/06/13 07:35
L8	1	("first mid-level signal" SAME "fault signal").clm.	US-PGP UB	AND	ON	2006/06/13 07:36

*Interference Search*